





**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT Sheet 2 of 2**

Docket No. B0004/7116

Applicant: Gerhard Weiß  
Serial No: 10/688,207  
Filed: October 17, 2003  
For: COMPACT VERY HIGH RESOLUTION TIME-OF-FLIGHT MASS  
SPECTROMETER  
Examiner: Not Yet Assigned  
Art Unit: Not Yet Assigned

**OTHER PRIOR ART – NON PATENT LITERATURE AND DOCUMENTS**

Exam Inits	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the articles (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T
		WILEY, W.C., et al., "Time-of-Flight Mass Spectrometer with Improved Resolution", The Review of Scientific Instruments, Vol. 26, No. 12, Bendix Aviation Corporation Research Laboratories, December 1955, pp. 1150-1157.	<input type="checkbox"/>
		BAKKER, J.M., "The Time-Focusing Principle: A Double-Focusing Design For Time-Of-Flight Mass Spectrometers", International Journal of Mass Spectrometry and Ion Physics, Vol. 6, Elsevier Publishing Company, Amsterdam, 1971, pp. 291-295.	<input type="checkbox"/>
		SYSOEV, Alexander A., et al., "Direct sampling time-of-flight mass spectrometers for technological analysis", Fresenius J. Anal Chem, Vol. 361, Springer-Verlag, 1998, pp. 261-266.	<input type="checkbox"/>
		SYSOEV, A.A., "Time-of-flight analysers with sector fields: advances and prospects", Eur. J. Mass Spectrom, Vol. 6, IM Publications, 2000, pp. 501-513.	<input type="checkbox"/>
		SAKURAI, T., et al., "A New Time-Of-Flight Mass Spectrometer", International Journal of Mass Spectrometry and Ion Processes, Vol. 66, No. 3, Elsevier Science Publishers B.V., 1985, pp. 283-290.	<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>

Examiner  
Signature

Date  
Considered